



2625

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of: Hamid K. Aghajan
Assignee: Applied Materials, Inc.
Atty. Dkt.: 006816 USA/PDC/EBI/OR
Serial No.: 09/365,517 Filed: August 2, 1999
Examiner: Sheela C. Chawan Group Art Unit: 2625
Title: Two-Dimensional Scatter Plot Technique for Defect Detection

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Technology Center 2600

Commissioner for Patents
Washington, D.C. 20231

Sir:

Transmitted herewith is a response to the Outstanding Office Action and a Terminal Disclaimer.
No claims have been added, and no additional filing fee is required.

Date: January 3, 2003

Respectfully submitted
By Michael B. Einschlag
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Enc. Response to an Office Action
Terminal Disclaimer

CERTIFICATE OF MAILING under 37 C.F.R. 1.8(a)

I hereby certify that this correspondence is being deposited on January 3, 2003 with the United States Postal Service as first class mail, with sufficient postage, in an envelope addressed to Commissioner for Patents, Washington, D.C. 20231.

Michael B. Einschlag
Michael B. Einschlag

January 3, 2003
Date of Signature